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# (54) AUTOMATIC FEATURE SELECTION SYSTEM FOR DATA CONTAINING MISSING VALUES

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# (57) ABSTRACT

An automatic feature selection system for test data with data (including the test data and/or the training data containing missing values in order to improve classifier performance. The missing features for such data are selected in one of two ways: first approach assumes each missing feature is uniformly distributed over its range of values whereas in the second approach, the number of discrete levels for each feature is increased by one for the missing features. These two choices modify the Bayesian Data Reduction Algorithm accordingly used for the automatic feature selection.

### 8 Claims, 2 Drawing Sheets

